

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,371	SHIUE ET AL.	
Examiner	Art Unit	
Jeffrey R. Snay	1743	

	SEAR	CHED	
Class	Subclass	Date	Examiner
436	164 166 172 92 96 63 86 808 810 811	6/20/2005	JRS
422	61	6/20/2005	JRS
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Subclass	Date	Examiner
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	Subclass	Subclass Date

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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